

### FEATURES

- 8-Bit Resolution
- Up to 10 MHz Sampling Rate
- Internal S/H Function
- Single Supply: 3.3V
- VIN DC Range: 0V to  $V_{DD}$
- VREF DC Range: 1V to  $V_{DD}$
- Low Power: 25mW typ. (excluding reference)

- Latch-Up Free
- ESD Protection: 2000V Minimum
- 20-Pin Package Available: XRD87L75

### APPLICATIONS

- Digital Color Copiers
- Cellular Telephones
- CCDs and Scanners
- Video Capture Boards

### GENERAL DESCRIPTION

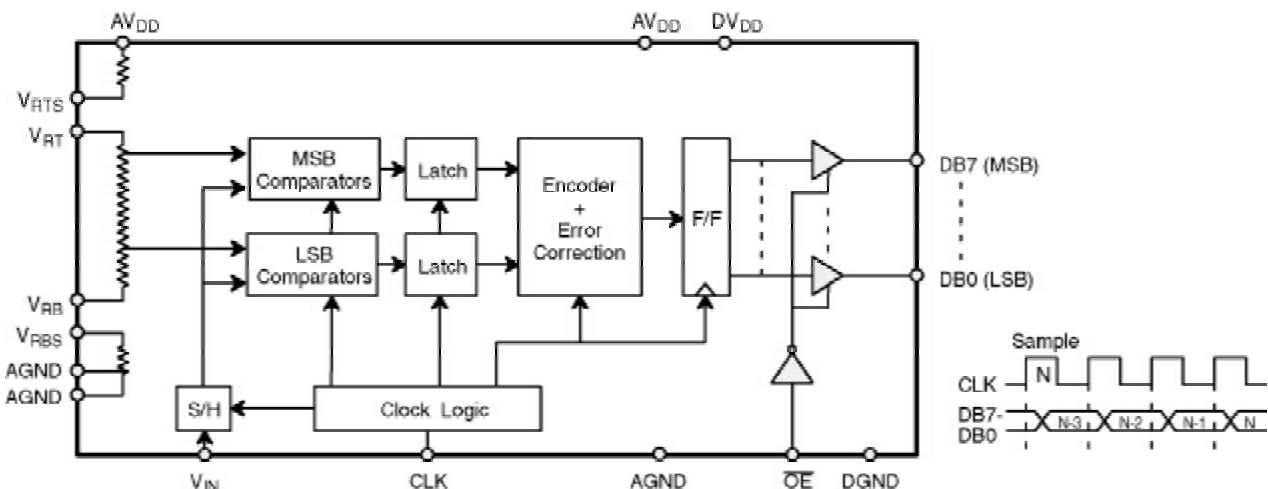
The XRD87L85 is an 8-bit Analog-to-Digital Converter. Designed using an advanced 3.3V CMOS process, this part offers excellent performance, low power consumption, and latch-up free operation.

This device uses a two-step flash architecture to maintain low power consumption at high conversion rates. The input circuitry of the XRD87L85 includes an on-chip S/H function which allows the user to digitize analog input signals between AGND and  $AV_{DD}$ . Careful design and chip layout have achieved a low analog input capacitance. This reduces “kickback” and eases the requirements of the buffer/amplifier used to drive the XRD87L85. The designer can choose the internally generated reference voltages by connecting  $V_{RB}$  to

$V_{RBS}$  and  $V_{RT}$  to  $V_{RTS}$ , or provide external reference voltages to the  $V_{RB}$  and  $V_{RT}$  pins. The internal reference generates 0.4V at  $V_{RB}$  and 1.72V at  $V_{RT}$ . Providing external reference voltages allows easy interface to any input signal range between AGND and  $AV_{DD}$ . This also allows the system to adjust these voltages to cancel zero scale and full scale errors, or to change the input range as needed.

The device operates from a single +3.3V supply. Power consumption is 25mW at FS = 6MHz. Specified for operation over the commercial/industrial (-40 to +85°C) temperature range, the XRD87L85 is available in Plastic Dual-in-line (PDIP), Surface Mount (SOIC) and Small Outline (SOP) packages in EIAJ and JEDEC.

### SIMPLIFIED BLOCK AND TIMING DIAGRAM

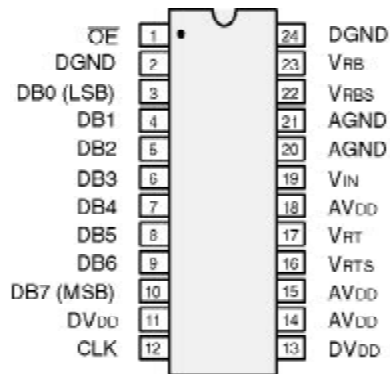


## ORDERING INFORMATION

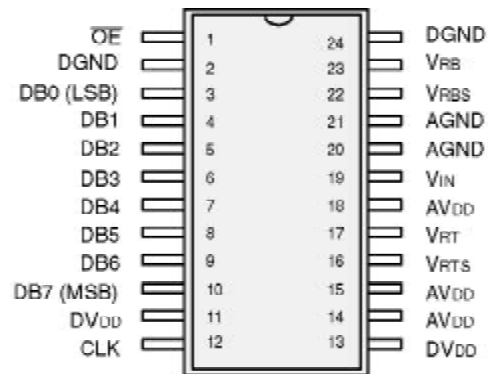
Package Type	Temperature Range	Part No.	DNL (LSB)	INL (LSB)
SOIC (Jedec)	-40 to +85°C	XRD87L85AID	+/- 0.5	+/-1.5
SOP (EIAJ)	-40 to +85°C	XRD87L85AIK	+/- 0.5	+/-1.5
Plastic Dip (300MIL)	-40 to +85°C	XRD87L85AIP	+/- 0.5	+/-1.5

## PIN CONFIGURATIONS

See Packaging Section for Package Dimensions



24-Pin PDIP (300 MIL) - P24



24-Pin SOP (EIAJ, 5.4mm) – K24  
24-Pin SOIC (Jedec, 300 MIL) – D24

## PIN OUT DEFINITIONS

PIN NO.	NAME	DESCRIPTION	PIN NO.	NAME	DESCRIPTION
1	$\overline{OE}$	Output Enable	13	DV <sub>DD</sub>	Digital Power Supply
2	DGND	Digital Ground	14	AV <sub>DD</sub>	Analog Power Supply
3	DB0	Data Output Bit 0 (LSB)	15	AV <sub>DD</sub>	Analog Power Supply
4	DB1	Data Output Bit 1	16	V <sub>RTS</sub>	Generates 1.72 V if tied to V <sub>RT</sub>
5	DB2	Data Output Bit 2	17	V <sub>RT</sub>	Top Reference
6	DB3	Data Output Bit 3	18	AV <sub>DD</sub>	Analog Power Supply
7	DB4	Data Output Bit 4	19	VIN	Analog Input
8	DB5	Data Output Bit 5	20	AGND	Analog Ground
9	DB6	Data Output Bit 6	21	AGND	Analog Ground
10	DB7	Data Output Bit 7 (MSB)	22	V <sub>RBS</sub>	Generates 0.4 V if tied to V <sub>RB</sub>
11	DV <sub>DD</sub>	Digital Power Supply	23	V <sub>RB</sub>	Bottom Reference
12	CLK	Sampling Clock Input	24	DGND	Digital Ground

## ELECTRICAL CHARACTERISTICS TABLE

UNLESS OTHERWISE SPECIFIED:  $AV_{DD} = DV_{DD} = 3.3V$ ,  $FS = 6MHz$  (50% DUTY CYCLE),  
 $V_{RT} = 2.5V$ ,  $V_{RB} = 0.5V$ ,  $T_A = 25^\circ C$

Parameter	Symbol	25°C			Units	Test Conditions/Comments
		Min	Typ	Max		
<b>KEY FEATURES</b>						
Resolution		8			Bits	
Sampling Rate	FS	0.1	6	10	MHz	
<b>ACCURACY</b>						
Differential Non-Linearity	DNL		+/-0.3	+/-0.5	LSB	Best Fit Line (Max INL – Min INL)/2
Integral Non-Linearity	INL		+/-0.75	+/-1.5	LSB	
Zero Scale Error	EZS		+3		LSB	
Full Scale Error	EFS		-2		LSB	
<b>REFERENCE VOLTAGES</b>						
Positive Ref. Voltage	$V_{RT}$		2.5	$AV_{DD}$	V	$V_{REF} = V_{RT} - V_{RB}$
Negative Ref. Voltage	$V_{RB}$	AGND	0.5		V	
Differential Ref. Voltage <sup>3</sup>	$V_{REF}$	1.0		$AV_{DD}$	V	
Ladder Resistance	$R_L$	245	350	550	$\Omega$	
Ladder Temp. Coefficient	$R_{TCO}$		2000		ppm/°C	
Self Bias 1						
Short $V_{RB}$ and $V_{RBS}$	$V_{RB}$		0.4		V	
Short $V_{RT}$ and $V_{RTS}$	$V_{RT}-V_{RB}$		1.72		V	
Self Bias 2						
$V_{RB} = AGND$ , Short $V_{RT}$ and $V_{RTS}$	$V_{RT}$		1.5		V	
<b>ANALOG INPUT</b>						
Input Bandwidth (-1 dB) <sup>2,4</sup>	BW		50		MHz	
Input Voltage Range	$V_{IN}$	$V_{RB}$		$V_{RT}$	V	
Input Capacitance <sup>5</sup>	$C_{IN}$		16		pF	
Aperture Delay <sup>2</sup>	$t_{AP}$		4		ns	
<b>DIGITAL INPUTS</b>						
Logical "1" Voltage	$V_{IH}$	2.5			V	$V_{IN} = DGND$ to $DV_{DD}$
Logical "0" Voltage	$V_{IL}$			0.5	V	
DC Leakage Current <sup>6</sup>	$I_{IN}$				$\mu A$	
CLK			5		$\mu A$	
$\overline{OE}$			5		$\mu A$	
Input Capacitance			5		pF	
Clock Timing ( See Figure 1.) <sup>7</sup>						
Clock Period	1/FS	100	166		ns	
High Pulse Width	$t_{PWH}$	50	83		ns	
Low Pulse Width	$t_{PWL}$	50	83		ns	
<b>DIGITAL OUTPUTS</b>						
Logical "1" Voltage	$V_{OH}$	2.5			V	$C_{OUT} = 15 pF$ $I_{LOAD} = 1 mA$ $I_{LOAD} = 1 mA$ $V_{OUT} = DGND$ to $DV_{DD}$
Logical "0" Voltage	$V_{OL}$			0.5	V	
3-state Leakage	$I_{OZ}$	-10		10	$\mu A$	
Data Valid Delay <sup>8</sup>	$t_{DL}$		12		ns	
Data Enable Delay	$t_{DEN}$		5		ns	
Data 3-state Delay	$t_{DHz}$		5		ns	

## ELECTRICAL CHARACTERISTICS TABLE (CONT'D)

UNLESS OTHERWISE SPECIFIED:  $AV_{DD} = DV_{DD} = 3.3V$ , FS = 6MHZ (50% DUTY CYCLE),

$V_{RT} = 2.5V$ ,  $V_{RB} = 0.5V$ ,  $T_A = 25^\circ C$

Parameter	Symbol	25°C			Units	Test Conditions/Comments
		Min	Typ	Max		
<b>ACPARAMETERS</b>						
Differential Gain Error	dg		2		%	FS = 4 x NTSC
Differential Phase Error	d <sub>ph</sub>		1		Degree	FS = 4 x NTSC
<b>POWERSUPPLIES</b>						
Operating Voltage ( $AV_{DD}$ , $DV_{DD}$ ) <sup>9</sup>	$V_{DD}$	3.0	3.3	3.6	V	
Current (AGND + DGND)	$I_{DD}$		8	12	mA	Does not include ref. current

### NOTES

- The difference between the measured and the ideal code width ( $V_{RE}/256$ ) is the DNL error (Figure 3). The INL error is the maximum distance (in LSBs) from the best fit line to any transition voltage (Figure 4). Accuracy is a function of the sampling rate (FS).
- Guaranteed, not tested
- Specified values guarantee functionality. Refer to other parameters for accuracy.
- 1dB bandwidth is a measure of performance of the A/D input stage (S/H + amplifier). Refer to other parameters for accuracy within the specified bandwidth.
- See  $V_{in}$  input equivalent circuit (Figure 5). Switched capacitor analog input requires driver with low output resistance.
- All inputs have diodes to  $DV_{DD}$  and DGND. Input DC currents will not exceed specified limits for any input voltage between DGND and  $DV_{DD}$ .
- $t_R$ ,  $t_F$  should be limited to >5ns for best results.
- Depends on the RC load connected to the output pin.
- AGND & DGND pins are connected through the silicon substrate. Connect together at the package and to the analog ground plane.

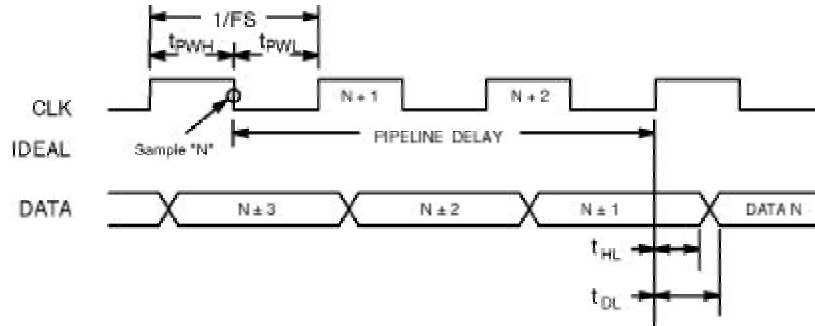
**Specifications are subject to change without notice**

## ABSOLUTE MAXIMUM RATINGS ( $T_A = +25^\circ C$ unless otherwise noted)<sup>1, 2, 3</sup>

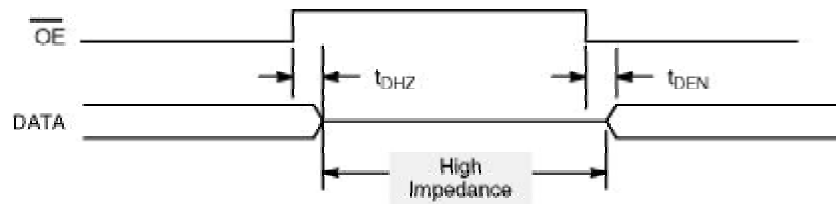
$V_{DD}$ to GND .....	5.5V	Storage Temperature .....	-65 to +150°C
$V_{RT}$ & $V_{RB}$ .....	$V_{DD} + 0.5$ to GND -0.5V	Lead Temperature (Soldering 10 seconds) ...	+300°C
$V_{IN}$ .....	$V_{DD} + 0.5$ to GND -0.5V	Package Power Dissipation Rating @ 75°C	
All Inputs .....	$V_{DD} + 0.5$ to GND -0.5V	PDIP, SOIC, SOP .....	675mW
All Outputs .....	$V_{DD} + 0.5$ to GND -0.5V	Derates above 75°C .....	12mW/°C

### NOTES:

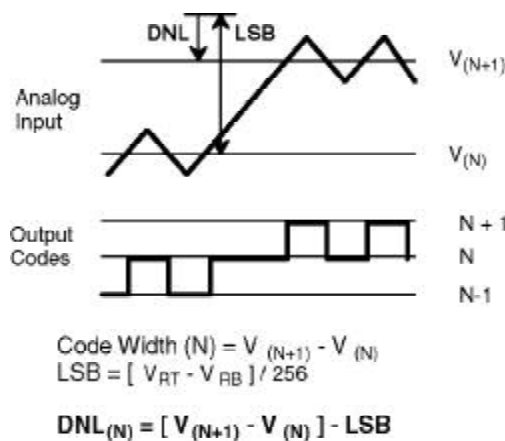
- Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation at or above this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.
- Any input pin which can see a value outside the absolute maximum ratings should be protected by Schottky diode clamps (HP5082-2835) from input pin to the supplies. All inputs have protection diodes which will protect the device from short transients outside the supplies of less than 100mA for less than 100ms.
- $V_{DD}$  refers to  $AV_{DD}$  and  $DV_{DD}$ . GND refers to AGND and DGND.



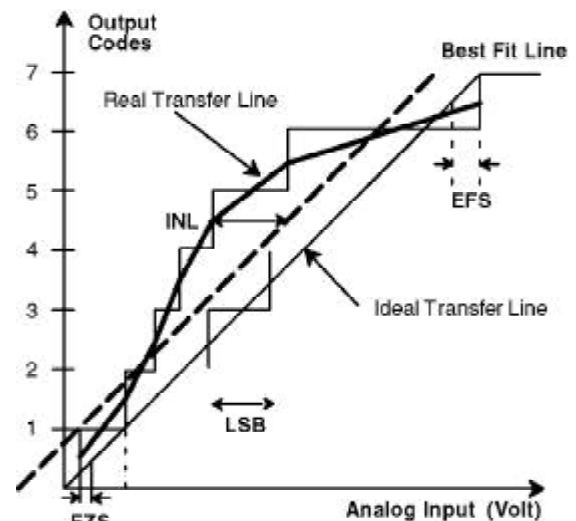
**Figure 1. XRD87L85 Timing Diagram**



**Figure 2. Output Enable/Disable Timing Diagram**



**Figure 3. DNL Measurement**



**Figure 4. INL Error Calculation**

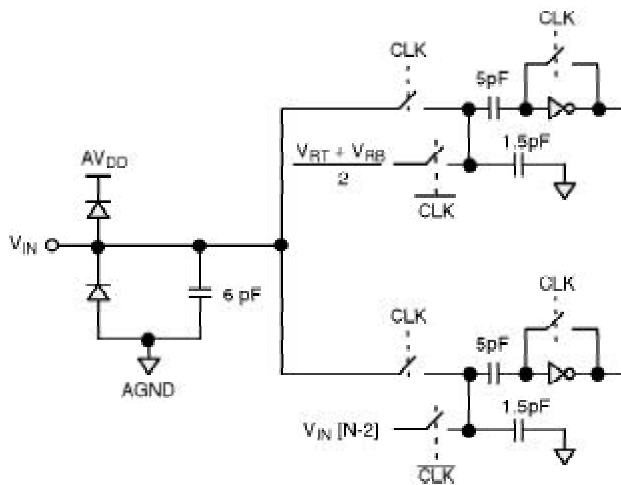


Figure 5. Equivalent Input Circuit

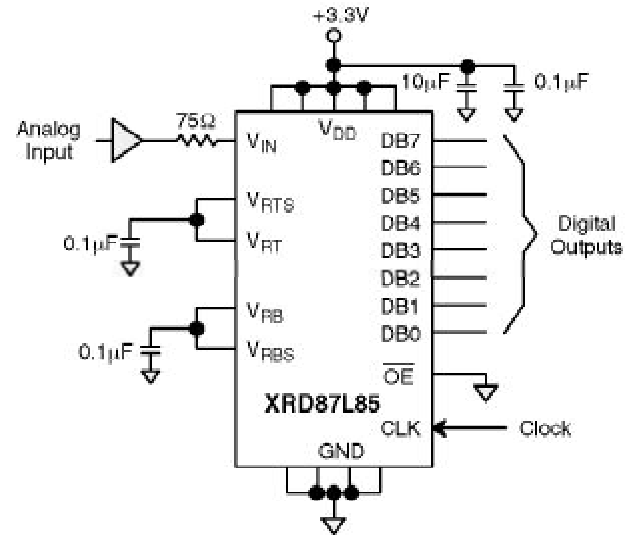


Figure 6. Typical Circuit Connections

## APPLICATION NOTES

Signals should not exceed  $V_{DD} + 0.5V$  or go below GND  $-0.5V$ . All pins have internal protection diodes that will protect them from short transients ( $<100\mu s$ ) outside the supply range.

AGND and DGND pins are connected internally through the P-substrate. DC voltage differences between GND pins will cause undesirable internal substrate currents.

The power supply ( $V_{DD}$ ) and reference voltage ( $V_{RT}$  &  $V_{RB}$ ) pins should be decoupled with  $0.1\mu F$  and  $10\mu F$  capacitors to AGND, placed as close to the chip as possible.

The digital outputs should not drive long wires or buses. The capacitive coupling and reflections will contribute noise to the conversion.

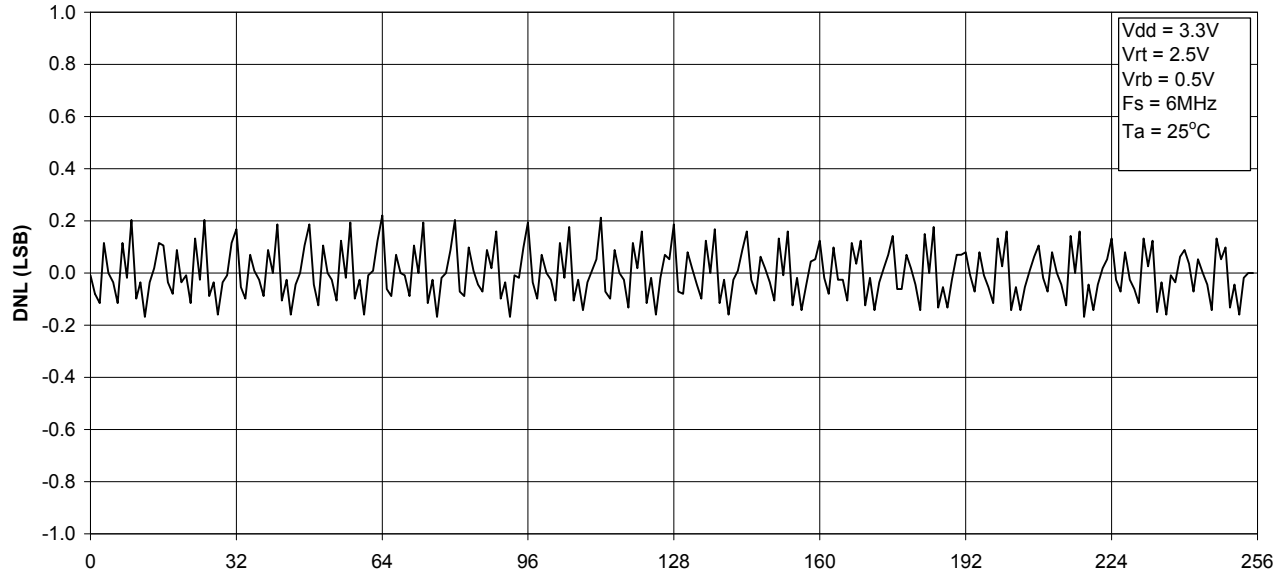
To avoid timing errors, use the rising edge of the sample clock (CLK) to latch data from the XRD87L85 to other parts of the system.

The reference can be biased internally by shorting  $V_{RT}$  to  $V_{RTS}$  and  $V_{RB}$  to  $V_{RBS}$ . This will generate  $0.4V$  at  $V_{RB}$  and  $1.72V$  at  $V_{RT}$  (see Figure 5).

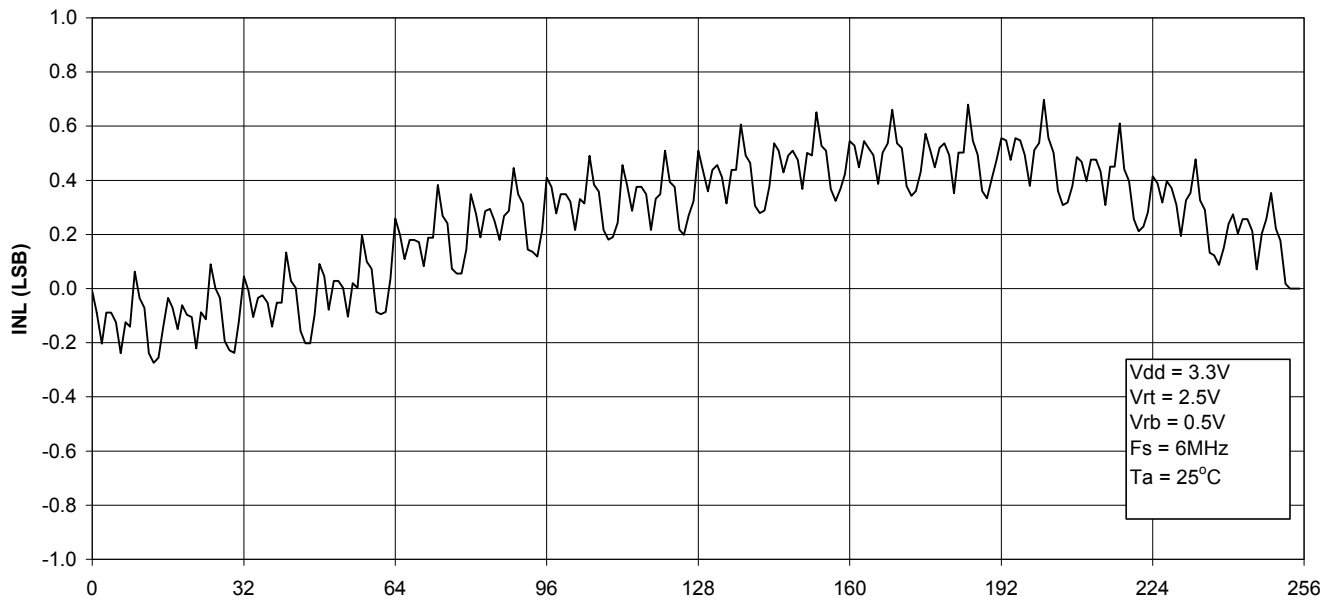
If the internal reference pins  $V_{RTS}$  and/or  $V_{RBS}$  are not used, they should be left unconnected.

The output enable pin ( $\overline{OE}$ ) should not be left unconnected. If not controlled by an active signal, then it must be tied to a logic low value.

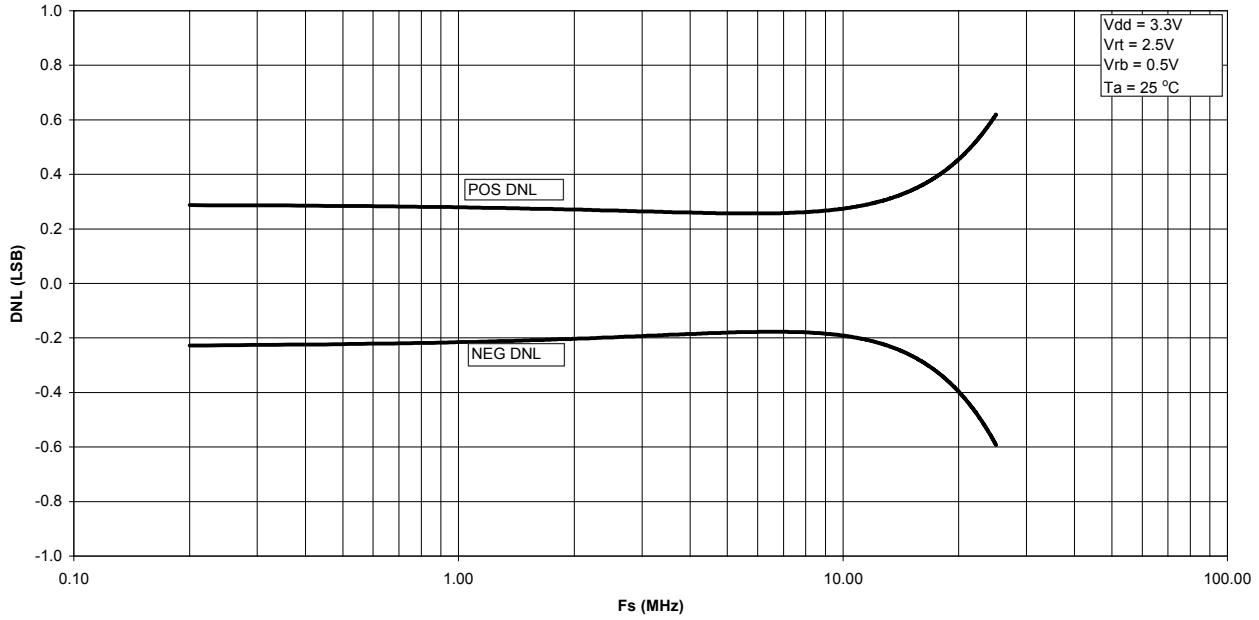
## PERFORMANCE CHARACTERISTICS



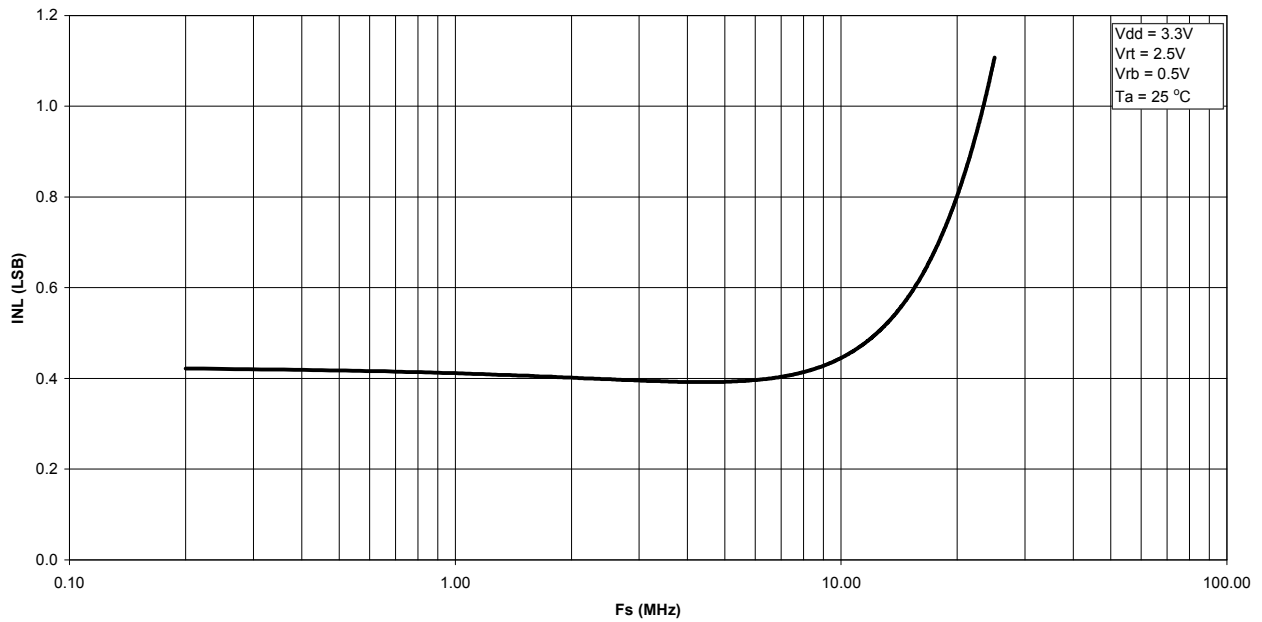
Graph 1. DNL vs. Code



Graph 2. INL vs. Code

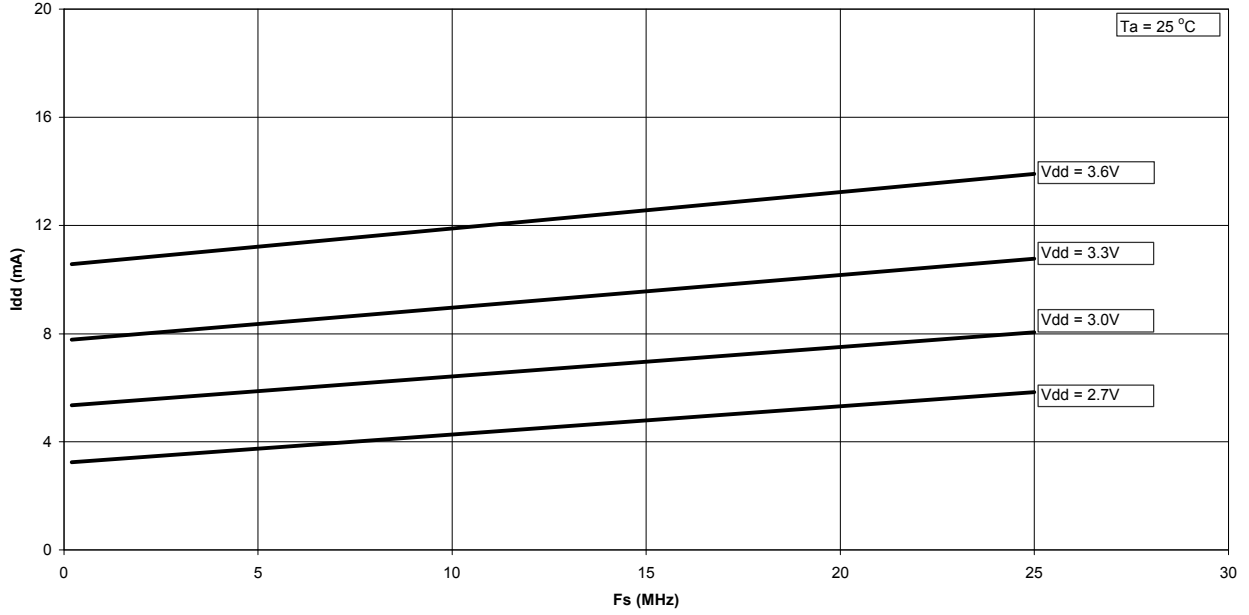


Graph 3. DNL vs. Sampling Frequency

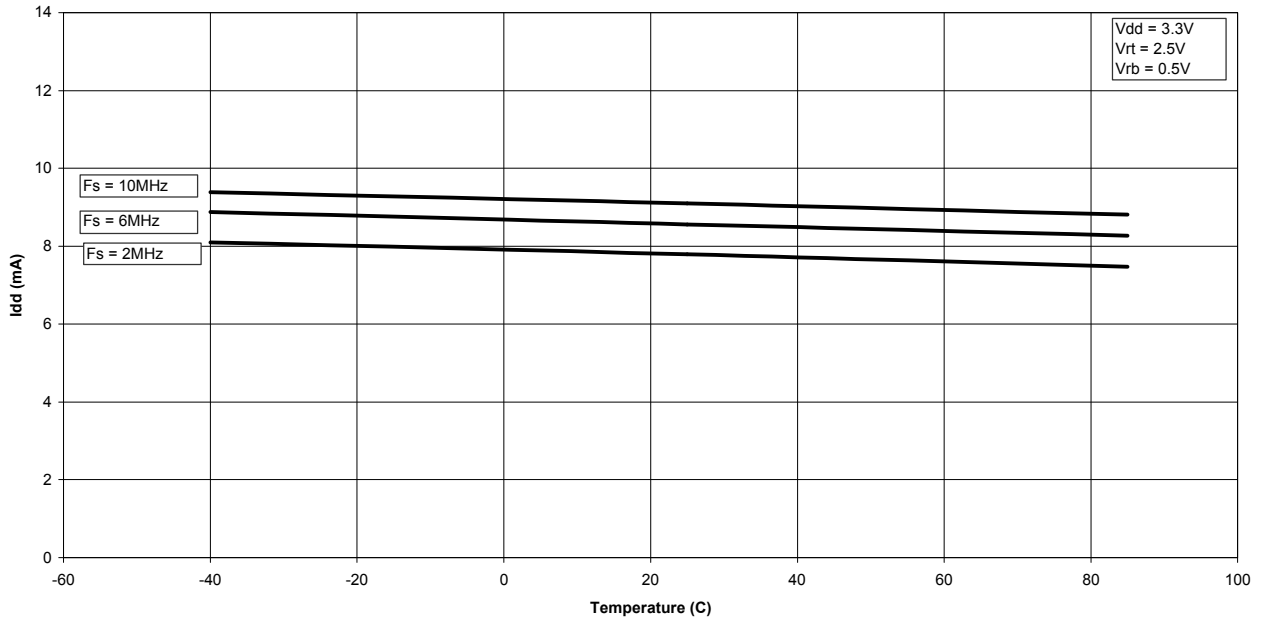


Graph 4. Best Fit INL vs. Sampling Frequency

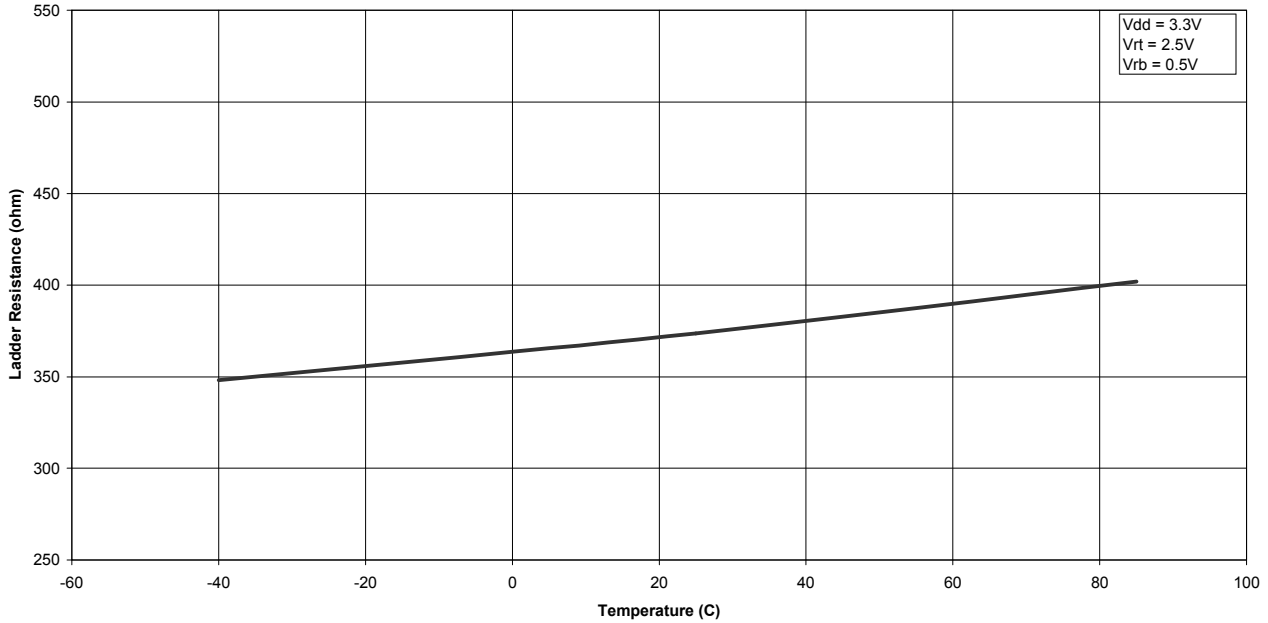




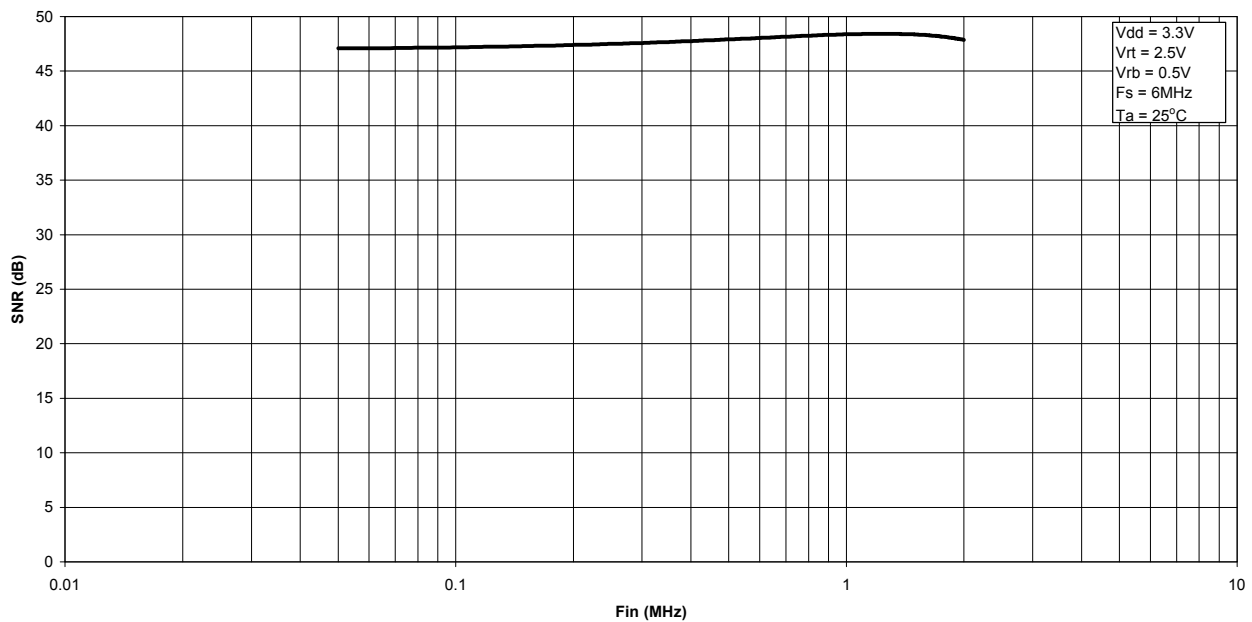
**Graph 5. IDD vs. Sampling Frequency**



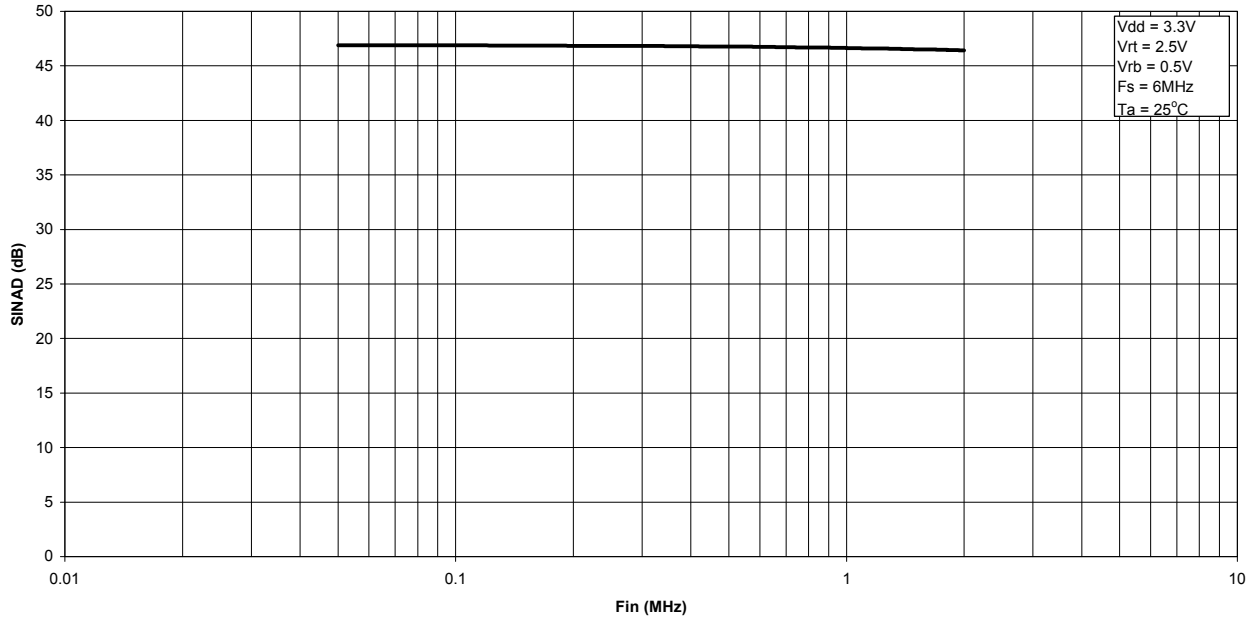
**Graph 6. Supply Current vs. Temperature**



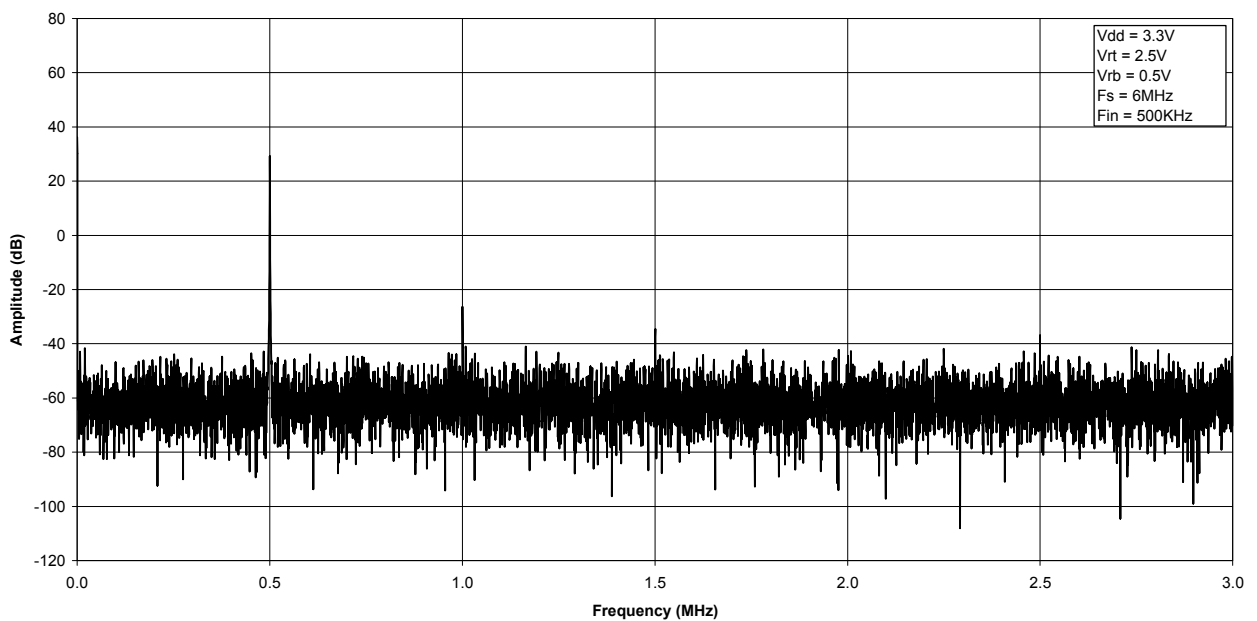
Graph 7. Ladder Resistance vs. Temperature



Graph 8. SNR vs. Input Frequency

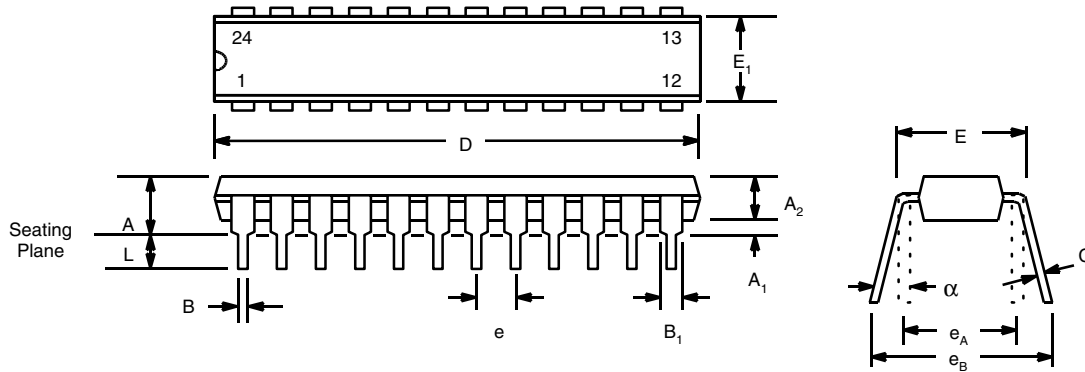


Graph 9. SINAD vs. Input Frequency



Graph 10. FFT Plot

**24 LEAD PLASTIC DUAL-IN-LINE  
(300 MIL PDIP)  
REV. 1.00**

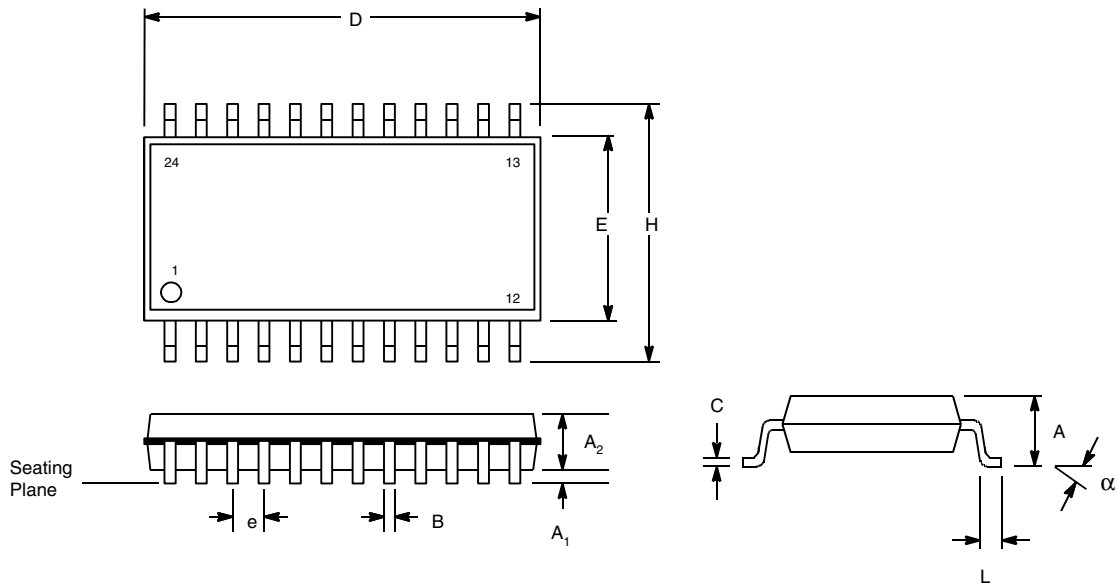


Note: The control dimension is the inch column

SYMBOL	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	0.145	0.210	3.68	5.33
A1	0.015	0.070	0.38	1.78
A2	0.115	0.195	2.92	4.95
B	0.014	0.024	0.36	0.56
B1	0.030	0.070	0.76	1.78
C	0.008	0.014	0.20	0.38
D	1.125	1.275	28.58	32.39
E	0.300	0.325	7.62	8.26
E1	0.240	0.280	6.10	7.11
e	0.100 BSC		2.54 BSC	
eA	0.300 BSC		7.62 BSC	
eB	0.310	0.430	7.87	10.92
L	0.115	0.160	2.92	5.08
a	0°	15°	0°	15°

**24 LEAD EIAJ SMALL OUTLINE  
(5.4 mm EIAJ SOP)**

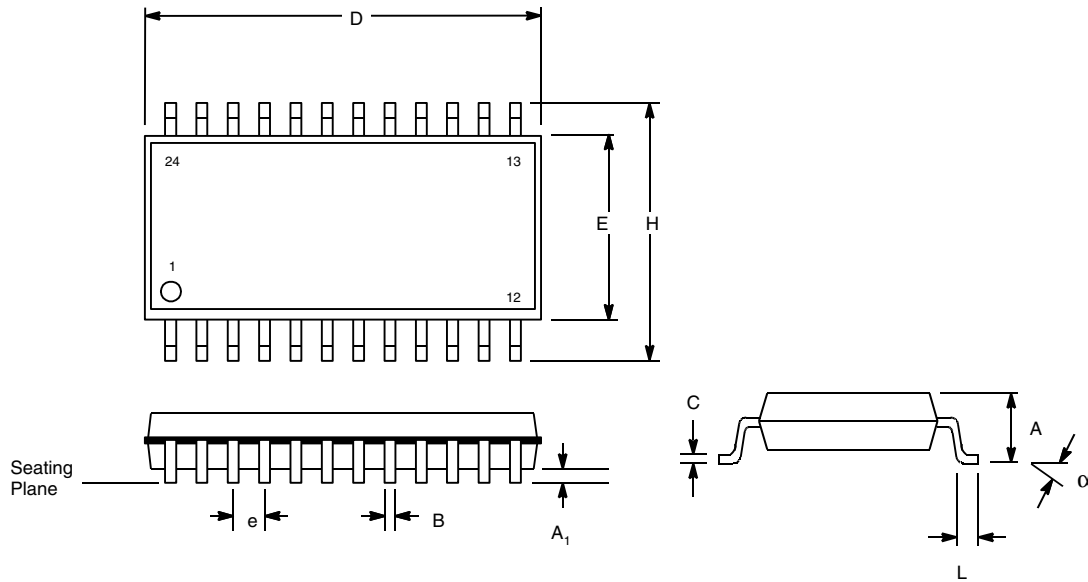
REV. 1.00



SYMBOL	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	0.069	0.083	1.75	2.10
A1	0.002	0.008	0.05	0.20
A2	0.067	0.075	1.70	1.90
B	0.012	0.020	0.30	0.50
C	0.004	0.008	0.10	0.20
D	0.587	0.594	14.90	15.10
E	0.209	0.217	5.30	5.50
e	0.050 BSC		1.27 BSC	
H	0.299	0.315	7.60	8.00
L	0.012	0.030	0.30	0.76
a	0°	10°	0°	10°

## 24 LEAD SMALL OUTLINE (300 MIL JEDEC SOIC)

REV. 1.00



SYMBOL	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	0.093	0.104	2.35	2.65
A1	0.004	0.012	0.10	0.30
B	0.013	0.020	0.33	0.51
C	0.009	0.013	0.23	0.32
D	0.598	0.614	15.20	15.60
E	0.291	0.299	7.40	7.60
e	0.050 BSC		1.27 BSC	
H	0.394	0.419	10.00	10.65
L	0.016	0.050	0.40	1.27
a	0°	8°	0°	8°

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